Issue Classification	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10560795	CORTEN ET AL.
	Examiner	Art Unit
	Wiehe, Nathan	3745

ORIGINAL		INTERNATIONAL CLASSIFICATION						
CLASS	**SUBCLASS**	**CLAIMED**					**NON-CLAIMED**	
416	1	F	0	3	D	11 / 04 (2006.0)	✓	
CROSS REFERENCE(S)		F	0	3	D	7 / 04 (2006.0)		
		F	0	3	B	15 / 06 (2006.01.01)		

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
416	198R	201R			
415	66				

Wiehe, Nathan *[signature]* 11/14/2007
(Assistant Examiner)   (Date)

[signature] EDWARD K. LOOK
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 3700

(Legal Instruments   (Date)
Examiner)

(Primary Examiner)   (Date) 11/20/07

Total Claims Allowed:

13 ✓

O.G. Print Claim(s)	O.G. Print Figure
1 ✓	2